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2022 IEEE International Conference On Artificial Intelligence Testing (AITest) AITest 2022

Table of Contents

Message from the General Chairs	vii	i
Message from the PC Chairs	i>	K
Organizers		K
Reviewers	. xi	i

2022 IEEE International Conference On Artificial Intelligence Testing (AITest)

Anomalous Anomaly Detection
Construction of Semantic Model for GUI of Mobile Applications Using Deep Learning
An Approach for Verifying And Validating Clustering Based Anomaly Detection Systems Using Metamorphic Testing
Supervised Learning for Coverage-Directed Test Selection in Simulation-Based Verification 19 Nyasha Masamba (University of Bristol, United Kingdom), Kerstin Eder (University of Bristol, United Kingdom), and Tim Blackmore (Infineon Technologies, United Kingdom)
Hybrid Intelligent Testing in Simulation-Based Verification
ML4ML: Automated Invariance Testing for Machine Learning Models

 A Passive Testing Approach using a Semi-Supervised Intrusion Detection Model for SCADA Network Traffic
Metrics for Measuring Error Extents of Machine Learning Classifiers
Original Music Generation using Recurrent Neural Networks with Self-Attention
DeepAbstraction: 2-Level Prioritization for Unlabeled Test Inputs in Deep Neural Networks 64 Hamzah Al-Qadasi (Univ. Grenoble Alpes, CNRS, France), Changshun Wu (Univ. Grenoble Alpes, CNRS, France), Yliès Falcone (Univ. Grenoble Alpes, Inria, CNRS, France), and Saddek Bensalem (Univ. Grenoble Alpes, CNRS, France)
MBET: Resilience Improvement Method for DNNs
 An Approach to GUI Test Scenario Generation Using Machine Learning
 A Review of Quality Assurance Research of Dialogue Systems
Generating Critical Driving Scenarios from Accident Sketches
DeltaExplainer: A Software Debugging Approach to Generating Counterfactual Explanations 103 Sunny Shree (The University of Texas at Arlington, USA), Jaganmohan Chandrasekaran (Virginia Tech, USA), Yu Lei (The University of Texas at Arlington, USA), Raghu N. Kacker (National Institute of Standards and Technology, USA), and D. Richard Kuhn (National Institute of Standards and Technology, USA)

Author Index	
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